

<b>Notice of References Cited</b>	Application/Control No. 09/628,261	Applicant(s)/Patent Under. Reexamination FRANKEL, MICHAEL Y.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,535,309	03-2003	Terahara, Takafumi	398/79
	B	US-5,920,414	07-1999	Miyachi et al.	398/91
	C	US-6,392,769	05-2002	Ford et al.	398/9
	D	US-6,449,074	09-2002	Okano et al.	398/91
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
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	N					
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,522,803	02-2003	Nakajima et al.	385/24
	B	US-5,907,420	05-1999	Chraplyvy et al.	398/180
	C	US-6,426,817	07-2002	Tomita, Takaharu	398/82
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
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